

# Senling Wang

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/5807864/publications.pdf>

Version: 2024-02-01

15  
papers

60  
citations

2682572

2  
h-index

2550090

3  
g-index

15  
all docs

15  
docs citations

15  
times ranked

11  
citing authors

#	ARTICLE	IF	CITATIONS
1	Compaction of Fault Dictionary without Degrading Diagnosis Ability. , 2021, , .		1
2	JTAG Security Threats: Current Attacks and Countermeasures. Journal of Japan Institute of Electronics Packaging, 2021, 24, 668-674.	0.1	0
3	FF-Control Point Insertion (FF-CPI) to Overcome the Degradation of Fault Detection under Multi-Cycle Test for POST. IEICE Transactions on Information and Systems, 2020, E103.D, 2289-2301.	0.7	2
4	Feasibility of Machine Learning Algorithm for Test Partitioning. , 2019, , .		0
5	Compact Dictionaries for Reducing Compute Time in Adaptive Diagnosis. , 2019, , .		0
6	Capture-Pattern-Control to Address the Fault Detection Degradation Problem of Multi-cycle Test in Logic BIST. , 2018, , .		3
7	Fault-detection-strengthened method to enable the POST for very-large automotive MCU in compliance with ISO26262. , 2018, , .		3
8	Automotive Functional Safety Assurance by POST with Sequential Observation. IEEE Design and Test, 2018, 35, 39-45.	1.2	7
9	A Method for Diagnosing Bridging Fault between a Gate Signal Line and a Clock Line. IEICE Transactions on Information and Systems, 2017, E100.D, 2224-2227.	0.7	0
10	Diagnosis Methods for Gate Delay Faults with Various Amounts of Delays. IPSJ Transactions on System LSI Design Methodology, 2016, 9, 13-20.	0.8	0
11	Structure-Based Methods for Selecting Fault-Detection-Strengthened FF under Multi-cycle Test with Sequential Observation. , 2016, , .		18
12	Diagnosis of Delay Faults Considering Hazards. , 2015, , .		0
13	Scan-Out Power Reduction for Logic BIST. IEICE Transactions on Information and Systems, 2013, E96.D, 2012-2020.	0.7	2
14	Low Power BIST for Scan-Shift and Capture Power. , 2012, , .		21
15	A Scan-Out Power Reduction Method for Multi-cycle BIST. , 2012, , .		3